# Analysis of Electromagnetic Noise From Switching Power Modules Using Wide Band Gap Semiconductors

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*Abstract*—The advancement of power electronics has driven the need for materials with superior electrical properties, leading to the use of wide band gap (WBG) semiconductors such as Silicon Carbide (SiC) and Gallium Nitride (GaN). These materials exhibit higher breakdown voltages, faster switching frequencies, and better thermal stability compared to conventional siliconbased devices [1], [2], [3]. However, these benefits introduce significant challenges in electromagnetic noise (EM noise) management, particularly due to rapid transitions characterized by high rates of change in voltage  $(dV/dt)$  and current  $(dI/dt)$ [4], [5]. This paper analytically investigates the sources and propagation of EM noise in high-frequency switching power modules using WBG semiconductors.

Mathematical models are derived to describe the noise generated, incorporating factors such as parasitic inductances  $(L)$ and capacitances  $(C)$ , frequency-dependent impedance  $(Z(f))$ , and noise power density  $(N(f))$  [6]. The relationships between switching characteristics and noise amplitude are explored through differential equations and Fourier analysis to map timedomain signals to their frequency components. Solutions for noise suppression are proposed, involving optimized circuit design and theoretical applications of electromagnetic wave propagation (EWP) principles, such as wave reflection and transmission in multi-layer structures [7], [8]. This work bridges theoretical electromagnetics with practical power module design, offering strategies that align with electromagnetic compatibility (EMC) standards and enhance performance.

## I. INTRODUCTION

The field of power electronics has witnessed a transformative shift with the integration of wide band gap (WBG) semiconductors, such as Silicon Carbide (SiC) and Gallium Nitride (GaN). These materials offer substantial advantages over conventional silicon devices, including higher breakdown voltage, increased thermal conductivity, and the ability to operate at higher switching frequencies [2], [5], [6]. Despite these benefits, the rapid switching speeds intrinsic to SiC and GaN introduce substantial electromagnetic noise (EM noise) into power systems. This EM noise can interfere with the stability and performance of electronic circuits, making electromagnetic compatibility (EMC) a critical aspect of design [4], [7].

Mathematically, the switching transients can be characterized by high rates of change in voltage  $\left(\frac{dV}{dt}\right)$  and current  $\left(\frac{dI}{dt}\right)$  [3]. These rapid transitions lead to significant electromagnetic interference (EMI), which can be modeled using Maxwell's equations and analyzed through their timeharmonic solutions [8]. Parasitic inductances (L) and capacitances (C) within circuit layouts contribute to noise propagation and resonance effects, which can be expressed in frequency domain terms through impedance functions:

$$
Z(f) = R + j\left(\omega L - \frac{1}{\omega C}\right)
$$

The challenge lies in mitigating these resonant peaks while maintaining system efficiency [6].

This paper aims to provide an analytical exploration of the mechanisms behind EM noise in WBG semiconductor-based power modules, supported by mathematical derivations and simulations. Fourier analysis and Laplace transforms are applied to model transient responses and noise behavior, linking theoretical electromagnetic wave propagation (EWP) concepts to practical solutions. The objective is to offer engineers and researchers a robust framework for designing power modules that adhere to EMC standards while leveraging the high performance of WBG semiconductors.

## II. LITERATURE REVIEW

The study of electromagnetic noise (EM noise) in power electronics has been an area of extensive research, particularly with the rise of wide band gap (WBG) semiconductors such as Silicon Carbide (SiC) and Gallium Nitride (GaN). Early studies focused on the limitations of silicon-based power modules, highlighting their inefficiencies at high frequencies due to thermal constraints and slower switching speeds [1], [5]. With the adoption of WBG materials, research has shifted toward analyzing the new challenges posed by their rapid switching characteristics [2], [3].

The mathematical modeling of EM noise in power modules often starts with circuit-level equations that account for parasitic components. Patel and Sharma [6] presented models based on Kirchhoff's laws integrated with differential equations to express voltage and current waveforms under transient conditions. The use of Fourier transforms:

$$
F(\omega) = \int_{-\infty}^{\infty} f(t)e^{-j\omega t}dt
$$

has been pivotal in translating time-domain noise into its frequency components for more detailed analysis [7].

Further studies by Huang et al. [2] demonstrated that the high  $dV/dt$  and  $dI/dt$  rates in WBG semiconductors produce significant noise, which can be approximated using partial differential equations (PDEs) derived from Maxwell's equations. These PDEs describe how the electric and magnetic fields behave in relation to circuit geometry and material properties [4], [8].

Techniques for mitigating EM noise have been proposed, ranging from snubber circuits to layout optimization. Snubber circuits can be modeled using second-order differential equations representing damping behavior to minimize oscillations at switching events. Advanced research, such as the work by Lee and Kim [7], applied transmission line theory to map noise propagation, using characteristic impedance:

$$
Z_0 = \sqrt{\frac{L}{C}}
$$

and reflection coefficients to identify resonant conditions. The implementation of multilayer PCB layouts was also suggested as an effective means of suppressing coupling effects [5].

Despite advancements, gaps remain in integrating theoretical electromagnetic wave propagation (EWP) principles with practical circuit design. This paper seeks to bridge these gaps by presenting mathematical models that align with realworld observations and proposing solutions to achieve EMC compliance in high-frequency WBG modules.

# III. PROPOSED SOLUTION

To address the challenges of electromagnetic noise in power modules utilizing wide band gap (WBG) semiconductors, a comprehensive, mathematically driven approach is proposed. This approach combines noise modeling, simulation, and practical design enhancements.

# *A. Mathematical Noise Modeling*

The behavior of EM noise in WBG semiconductors is modeled using differential equations that describe current and voltage waveforms under rapid switching. The governing equations take the form:

$$
L\frac{di(t)}{dt} + Ri(t) + \frac{1}{C} \int i(t)dt = V_{in}(t)
$$
 (1)

where  $L$  and  $C$  represent parasitic inductance and capacitance, respectively [6], [8]. The Fourier transform of these equations provides a frequency-domain representation essential for analyzing noise behavior:

$$
I(\omega) = \frac{V_{in}(\omega)}{R + j\omega L - \frac{1}{j\omega C}}
$$
 (2)

This analysis helps determine the frequency ranges where noise peaks occur due to resonance effects [3].

# *B. Simulation of Noise Propagation*

Simulations are conducted using MATLAB and ANSYS to solve these equations numerically and visualize noise propagation. The simulations highlight the impact of high  $dV/dt$ and  $dI/dt$  rates on EM noise distribution and identify critical frequency components. These tools are widely recognized for their precision in modeling power electronics and electromagnetic behavior [5], [7].

# *C. Mitigation Techniques*

The proposed strategies for noise suppression include:

- Optimized Gate Drivers: Adjusting gate resistance  $(R_G)$ to control switching speed and reduce  $dV/dt$  [6].
- Snubber Circuits: Implementing RC snubber networks modeled by:

$$
V_{RC}(t) = V_0 e^{-\frac{t}{RC}}
$$
 (3)

to dampen oscillations and minimize high-frequency noise [7].

- Multilayer PCB Layouts: Enhancing layout designs to reduce noise coupling by optimizing ground planes and minimizing loop inductance [5].
- EWP Concepts: Using electromagnetic wave propagation principles, wave impedance  $(Z_0)$  and reflection coefficients (Γ) are calculated to identify noise hotspots:

$$
\Gamma = \frac{Z_{load} - Z_0}{Z_{load} + Z_0} \tag{4}
$$

These metrics guide circuit optimizations [8].

# IV. ALGORITHMS

The algorithms developed for analyzing and mitigating electromagnetic noise in WBG semiconductor-based power modules are detailed below. Each algorithm incorporates mathematical formulations to achieve accurate modeling and optimization.

# *A. Noise Modeling Algorithm*

This algorithm provides a structured approach to analyzing EM noise in power modules.

[h] Noise Modeling Algorithm [1] **Input:** Switching frequency  $(f_s)$ ,  $dV/dt$ ,  $dI/dt$ , parasitic inductance  $(L)$ , parasitic capacitance  $(C)$ . Initialize circuit parameters and create the equivalent circuit model [6]. Solve the differential equation:

$$
L\frac{di(t)}{dt} + Ri(t) + \frac{1}{C} \int i(t)dt = V_{in}(t)
$$
 (5)

Apply the Fourier transform to derive the frequency spectrum:

$$
I(\omega) = \frac{V_{in}(\omega)}{R + j\omega L - \frac{1}{j\omega C}}
$$
(6)

Identify critical frequencies with peak noise levels [4]. Output: Frequency-domain representation of noise behavior.

# *B. EMI Mitigation Algorithm*

This algorithm provides a step-by-step process to optimize circuit behavior and reduce electromagnetic noise.

[h] EMI Mitigation Algorithm [1] **Input:** Circuit topology, gate resistance  $(R_G)$ , snubber circuit parameters  $(R, C)$ . Simulate circuit behavior with varying gate resistance and snubber configurations [5]. Optimize layout to minimize loop inductance and coupling effects [7]. Calculate EMI reduction metrics and compare pre- and post-mitigation results. Iterate on design parameters for further improvements. Output: Optimized configuration for minimized EMI.

# *C. EWP-Based Noise Propagation Algorithm*

This algorithm integrates electromagnetic wave propagation principles to analyze noise propagation in circuit layouts.

[h] EWP-Based Noise Propagation Algorithm [1] Input: Wave impedance  $(Z_0)$ , reflection coefficient (Γ), circuit geometry. Model noise propagation using transmission line theory:

$$
V(x) = V_0 \left( e^{-\gamma x} + \Gamma e^{\gamma x} \right) \tag{7}
$$

where  $\gamma$  is the propagation constant [7]. Calculate reflections at discontinuities:

$$
\Gamma = \frac{Z_{load} - Z_0}{Z_{load} + Z_0} \tag{8}
$$

Map noise energy distribution across circuit nodes to identify critical areas for mitigation. Output: Noise propagation profile for targeted EMI mitigation.

## V. IMPLEMENTATION

The practical application of the proposed algorithms was conducted through detailed simulations and analyses. This section describes the methods and tools used to validate the mathematical models and mitigation techniques.

# *A. Circuit Modeling and Simulation*

MATLAB and ANSYS Electronics Desktop were employed for circuit simulation. Parameters such as switching frequency (500 kHz to 5 MHz), parasitic inductances, and capacitances were varied to replicate real-world scenarios [5], [7]. These tools allowed for precise modeling of transient behaviors and provided insight into the frequency-domain characteristics of electromagnetic noise.

# *B. Numerical Solutions*

Differential equations representing circuit behavior were solved using numerical integration techniques, including Runge-Kutta methods, to ensure accurate time-domain analysis [3], [6]. Fourier transforms were applied to convert results to the frequency domain, enabling identification of critical noise frequencies.

# *C. Validation of Mitigation Strategies*

Gate driver optimization and RC snubber circuits were tested for their effectiveness in reducing EMI. Noise reduction was verified by comparing baseline and post-mitigation frequency spectra, demonstrating reductions of up to 20 dB at key frequencies [7], [8].

# VI. TESTING

The testing phase involved evaluating the effectiveness of the proposed noise mitigation techniques under various operating conditions, using MATLAB and ANSYS simulations [5], [7].

#### *A. Setup and Evaluation Metrics*

The simulation setup was configured to replicate real-world conditions, focusing on high  $dV/dt$  and  $dI/dt$  scenarios typical of WBG semiconductors. Key evaluation metrics included:

- Peak electromagnetic interference (EMI) levels in decibels (dB).
- Resonance analysis using impedance calculations at key nodes.
- Reduction in noise power density across critical frequency bands [6], [8].

## *B. Testing Procedure*

- 1) Baseline Analysis: Initial measurements of EMI were recorded without applying any mitigation strategies to establish a benchmark.
- 2) Application of Algorithms: The proposed algorithms for noise modeling and mitigation were applied sequentially to analyze their individual impact [3], [7].
- 3) Combination of Techniques: Optimized gate drivers, RC snubber circuits, and PCB layout improvements were combined to evaluate cumulative noise reduction.
- 4) Frequency-Domain Analysis: Fourier transforms were applied to validate reductions in specific frequency bands with MATLAB and ANSYS tools [5], [6].

#### *C. Results and Observations*

The results demonstrated significant improvements in EMI reduction:

- Gate driver optimization achieved an average EMI reduction of 12 dB by limiting  $dV/dt$  rates.
- RC snubber circuits provided an additional 8–10 dB reduction by damping oscillations at switching events [4], [5].
- When combined, the total EMI reduction exceeded 20 dB at critical frequencies, validating the effectiveness of multilayer PCB layouts in minimizing noise coupling and resonance effects [7], [8].

These results confirmed that the proposed techniques effectively reduce electromagnetic noise while maintaining circuit performance, aligning with industry standards for electromagnetic compatibility (EMC).

# VII. CONCLUSION

This study has provided a comprehensive analysis of electromagnetic noise in switching power modules that utilize wide band gap (WBG) semiconductors, with a focus on mathematical modeling and practical mitigation techniques. Through the development and application of differential equations, Fourier transforms, and transmission line theory, the mechanisms underlying EM noise generation were explored in detail.

Key outcomes included:

- Identification of critical noise frequencies.
- Implementation of gate driver optimization, RC snubber circuits, and multilayer PCB layout improvements.
- Validation of mitigation strategies through MATLAB and ANSYS simulations, showing EMI reductions of up to 20 dB [5], [7].

The results confirmed that using these mathematical approaches aligns with electromagnetic compatibility (EMC) standards, improving the reliability and performance of power modules. Future work can build on these findings by incorporating advanced materials, machine learning algorithms, and experimental validations to push the boundaries of WBG applications further. The research presented here serves as a foundation for developing efficient, compliant power systems and contributes valuable insights for engineers and researchers dedicated to advancing power electronics.

# VIII. FUTURE ENHANCEMENTS

While this study provides comprehensive models and effective strategies for managing electromagnetic noise in WBG semiconductor-based power modules, there are several areas where future work could enhance these findings. Potential directions for further research include:

# *A. Advanced Material Research*

Exploring alternatives such as Diamond and Aluminum Nitride (AlN) that offer higher thermal conductivity and breakdown strength could lead to improved EMI performance. New mathematical models can be developed to account for the properties of these materials [2], [6].

## *B. Machine Learning Integration*

Applying machine learning algorithms to dynamically optimize circuit configurations could automate the tuning of parameters such as gate resistance  $(R_G)$  and snubber components, enhancing design efficiency [8].

# *C. Experimental Validation*

Building and testing physical prototypes would validate the simulation results and provide real-world insights into the effectiveness of the proposed strategies [7].

# *D. Multilayer PCB Designs*

Investigating the impact of multilayer PCB layouts on noise propagation and EMI suppression through detailed modeling could yield new design strategies [5], [8].

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